

## APT20M18B2VFR A20M18LVFR 200V 100A 0.018Ω

**B2VFR** 

## POWER MOS V<sup>®</sup> FREDFET

Power MOS V<sup>®</sup> is a new generation of high voltage N-Channel enhancement mode power MOSFETs. This new technology minimizes the JFET effect, increases packing density and reduces the on-resistance. Power MOS V<sup>®</sup> also achieves faster switching speeds through optimized gate layout.

- T-MAX<sup>™</sup> or TO-264 Package
- Avalanche Energy Rated

Faster Switching

FAST RECOVERY BODY DIODE



# G

#### MAXIMUM RATINGS

All Ratings:  $T_{C} = 25^{\circ}C$  unless otherwise specified.

Symbol	Parameter	APT20M18B2VFR_LVFR	UNIT	
V <sub>DSS</sub>	Drain-Source Voltage	200	Volts	
I <sub>D</sub>	Continuous Drain Current <sup>©</sup> @ T <sub>C</sub> = 25°C	100	Amps	
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	400	711100	
V <sub>GS</sub>	Gate-Source Voltage Continuous	±30	Volts	
V <sub>GSM</sub>	Gate-Source Voltage Transient	±40	Volto	
D	Total Power Dissipation @ $T_{C} = 25^{\circ}C$	625	Watts	
P <sub>D</sub>	Linear Derating Factor	5.00	W/°C	
T_,T <sub>STG</sub>	Operating and Storage Junction Temperature Range	-55 to 150	°C	
Τ <sub>L</sub>	Lead Temperature: 0.063" from Case for 10 Sec.	300	Ŭ	
I <sub>AR</sub>	Avalanche Current $^{(1)}$ (Repetitive and Non-Repetitive)	100	Amps	
E <sub>AR</sub>	Repetitive Avalanche Energy <sup>①</sup>	50	mJ	
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>④</sup>	3000	1110	

#### STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage ( $V_{GS} = 0V, I_{D} = 250\mu A$ )	200			Volts
R <sub>DS(on)</sub>	Drain-Source On-State Resistance <sup>(2)</sup> ( $V_{GS}$ = 15V, $I_{D}$ = 50A)			0.018	Ohms
I <sub>DSS</sub>	Zero Gate Voltage Drain Current ( $V_{DS}$ = 200V, $V_{GS}$ = 0V)			250	μA
	Zero Gate Voltage Drain Current ( $V_{DS}$ = 160V, $V_{GS}$ = 0V, $T_{C}$ = 125°C)			1000	
I <sub>GSS</sub>	Gate-Source Leakage Current ( $V_{GS} = \pm 30V$ , $V_{DS} = 0V$ )			±100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage ( $V_{DS} = V_{GS}$ , $I_{D} = 2.5mA$ )	2		4	Volts

CAUTION: These Devices are Sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

### **DYNAMIC CHARACTERISTICS**

#### APT20M18B2VFR LVFR

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> = 0V		9880		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 25V		2320		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1 MHz		700		
Qg	Total Gate Charge <sup>③</sup>	V <sub>GS</sub> = 10V		330		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DD</sub> = 150V		55		nC
Q <sub>gd</sub>	Gate-Drain ("Miller") Charge	I <sub>D</sub> = 100A @ 25°C		145		
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>GS</sub> = 15V		18		
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 150V		27		ns
t <sub>d(off)</sub>	Turn-off Delay Time	I <sub>D</sub> = 100A @ 25°C		55		115
t <sub>f</sub>	Fall Time	R <sub>G</sub> = 0.6Ω		6		

#### SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

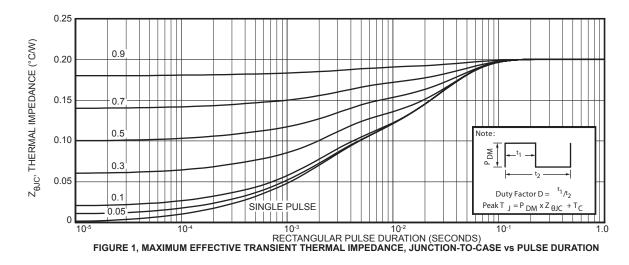
Symbol	Characteristic / Test Conditions		MIN	TYP	MAX	UNIT
۱ <sub>s</sub>	Continuous Source Current (Body Diode)				100	Amps
I <sub>SM</sub>	Pulsed Source Current <sup>①</sup> (Body Diode)				400	7 (11)00
V <sub>SD</sub>	Diode Forward Voltage <sup>(2)</sup> ( $V_{GS} = 0V$ , $I_{S} = -100A$ )				1.3	Volts
dv/dt	Peak Diode Recovery <sup>dv</sup> / <sub>dt</sub> <sup>⑤</sup>				8	V/ns
+	Reverse Recovery Time	T <sub>i</sub> = 25°C			230	0 ns
t <sub>rr</sub>	(I <sub>S</sub> = -100A, <sup>di</sup> / <sub>dt</sub> = 100A/µs)	T <sub>i</sub> = 125°C			450	115
0	Reverse Recovery Charge	T <sub>i</sub> = 25°C		0.9		μC
Q <sub>rr</sub>	(I <sub>S</sub> = -100A, <sup>di</sup> / <sub>dt</sub> ≤≤= 100A/µs)	T <sub>i</sub> = 125°C		3.4		μΟ
	Peak Recovery Current	T <sub>i</sub> = 25°C		11		Amps
RRM	(I <sub>S</sub> = -100A, <sup>di</sup> / <sub>dt</sub> = 100A/µs)	T <sub>i</sub> = 125°C		20		Amps

#### THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{_{ extsf{ heta}JC}}$	Junction to Case			0.20	°C/W
R <sub>θJA</sub>	Junction to Ambient			40	

- ① Repetitive Rating: Pulse width limited by maximum junction temperature
- O Pulse Test: Pulse width < 380 µs, Duty Cycle < 2%
- 3 See MIL-STD-750 Method 3471

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



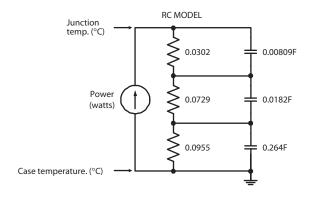
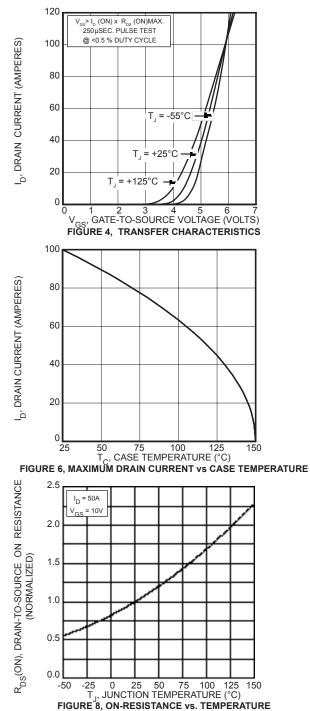
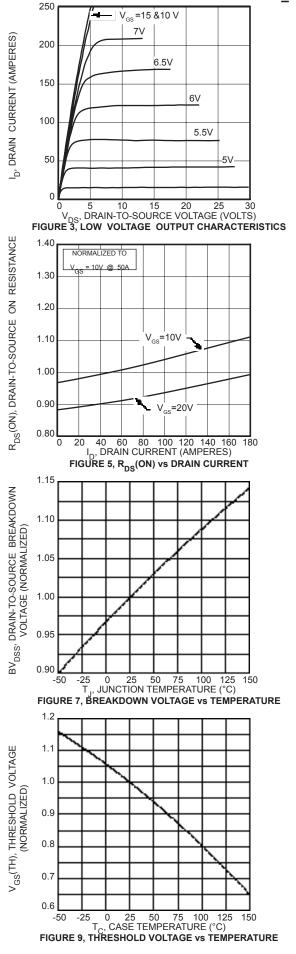
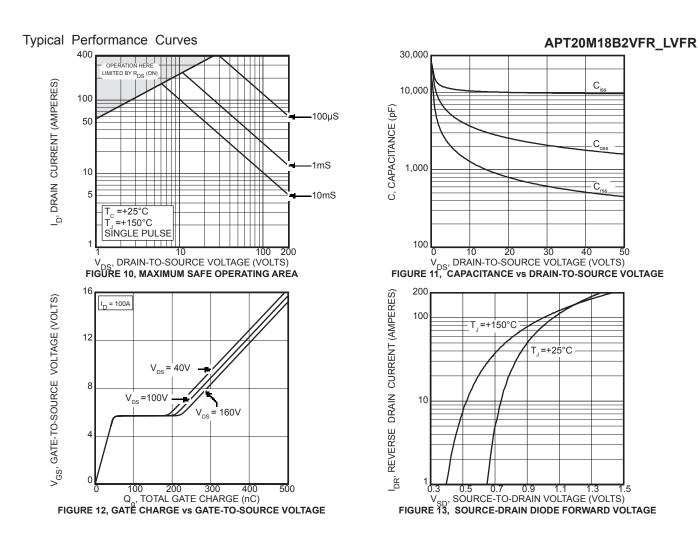


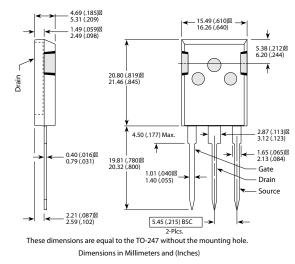
FIGURE 2, TRANSIENT THERMAL IMPEDANCE MODEL



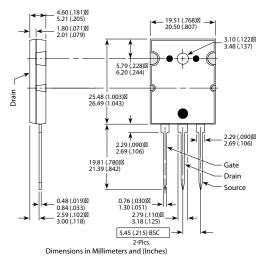




T-MAX<sup>™</sup> (B2) Package Outline (B2VFR)



TO-264 (L) Package Outline (LVFR)





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